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Class	Subclass
ISSUE CLASSIFICATION	

PATENT NUMBER

U.S. UTILITY Patent Application

<p><i>MR</i> O.I.P.E.</p> <p>SCANNED <i>GH</i> O.A. <i>Am</i></p>	<p>PATENT DATE</p>
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APPLICATION NO. 09/903601	CONT/PRIOR F	CLASS 382	SUBCLASS 145	ART UNIT 2623	EXAMINER J. Marcuso
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APPLICANTS

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Semiconductor wafer pattern shape evaluation method and device

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PTO-2040
12/89.

ISSUING CLASSIFICATION								
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CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
INTERNATIONAL CLASSIFICATION								

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
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Amount Due			Date Paid	
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